FCMN 2022 - International Conference on Frontiers of Characterization and Metrology for Nanoelectronics

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Title	FCMN 2022 - International Conference on Frontiers of Characterization and Metrology for Nanoelectronics
When	Mo, 14. März 2022 - Do, 17. März 2022

Description

FCMN 2022 - International Conference on Frontiers of Characterization and Metrology for Nanoelectronics

The FCMN will bring together scientists and engineers interested in all aspects of the characterization technology needed for nanoelectronic materials and device research, development, integration, and manufacturing.

All approaches are welcome: chemical, physical, electrical, magnetic, optical, in situ, and real-time control and monitoring.

The semiconductor industry is evolving rapidly: the conference will highlight major issues and provide critical reviews of important materials and structure characterization and nearline/inline metrology methods, including hardware, data analysis, and AI and machine learning, as the industry both extends the technology deep into the nanoscale and increases the diversity of devices and systems.

The conference consists of formal invited presentation sessions and poster sessions for contributed papers. The poster papers cover new developments in materials and structure characterization/metrology down to the nanoscale.

Learn more about this event by visiting following website:

https://fcmn2022.avs.org/

Venue - Monterey

Location	Monterey
City	Monterey
County	California CA
Country	US